IEEE EDS Kansai Chapter Awards 2014

■ IEEE EDS Kansai Chapter of the Year of the Year Award

Authors: **Yukihiro Kaneko**
Title: “Neural Network based on a Three-Terminal Ferroelectric Memristor”
Coauthors: Y. Nishitani, M. Ueda, and A. Tsujimura
Affiliation: Panasonic Corp.

■ IEEE EDS Kansai Chapter MFSK Award

Authors: **Takayuki Uchida[1]**
Title: “Fabrication of Aluminum Oxide Thin Films by Solution-Source Non-Vacuum Process of Mist Chemical Vapor Deposition with Ozone Assistance”
Coauthors: T. Kawaharamura[2], M. Furuta[2], and S. Fujita[1]
Affiliation: [1]Kyoto Univ., [2]Kochi Univ. Tech.

■ IEEE EDS Kansai Chapter IMFEDK Best Paper Award

Authors: **Chaiyanan Kulchaisit, Mami Fujii, Yoshihiro Ueoka, Juan Paolo Bermundo, Masahiro Horita, Yasuaki Ishikawa, and Yukiharu Uraoka**
Paper-ID: B-3
Title: “Reliability of Bottom Gate Amorphous InGaZnO Thin-Film Transistors with Siloxane Passivation Layer”
Affiliation: NAIST

■ IEEE EDS Kansai Chapter IMFEDK Student Paper Award

Authors: **Hiroshi Oka**
Paper-ID: PA-01
Title: “Schottky Barrier Height Reduction of NiGe/Ge Junction by P Ion Implantation for Metal Source/Drain Ge CMOS Devices”
Coauthors: Y. Minoura, T. Hosoi, T. Shimura, and H. Watanabe
Affiliation: Osaka Univ.

Authors: **Takuma Kobayashi**
Paper-ID: PB-01
Title: “Conduction-Type Dependence of Thermal Oxidation Rate on SiC(0001)”
Coauthors: J. Suda and T. Kimoto
Affiliation: Kyoto Univ.

Authors: **Takuya Kakegami**
Paper-ID: PB-02
Title: “Study of current collapse in AlGaN/GaN HEMTs passivated with sputter-deposited SiO_2 and SiN_x”
Coauthors: S. Ohi, K. P. Sengendo, H. Tokuda, and M. Kuzuhara
Affiliation: Univ. Fukui

Authors: **Go Wakimura**
Paper-ID: PB-03
Title: “Mechanism of off-leakage current in InGaZnO thin-film transistors”
Coauthors: Y. Yamauchi, Y. Matsuoka, and Y. Kamakura
Affiliation: Osaka Univ.

Authors: **Takahiro Yamaguchi**
Paper-ID: PC-03
Title: “Noise Performance of an Implantable Self-reset CMOS Image sensor”
Coauthors: Y. Sunaga, M. Haruta, T. Noda, K. Sasagawa, Y. Tokuda, and J. Ohta
Affiliation: NAIST